- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

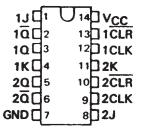
description

The '107 contain two independent J-K flip-flops with individual J-K, clock, and direct clear inputs. The '107 is a positive pulse-triggered flip-flop. The J-K input data is loaded into the master while the clock is high and transferred to the slave and the outputs on the high-to-low clock transistion. For these devices the J and K inputs must be stable while the clock is high.

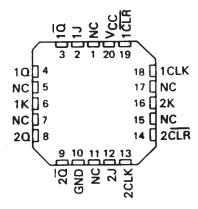
The 'LS107A contain two independent negative-edge-triggered flip-flops. The J and K inputs must be stable prior to the high-to-low clock transition for predictable operation. When the clear is low, it overrides the clock and data inputs forcing the Q output low and the $\overline{\mathbf{Q}}$ output high.

The SN54107 and the SN54LS107A are characterized for operation over the full military temperature range of -55 °C to 125 °C. The SN74107 and the SN74LS107A are characterized for operation from 0 °C to 70 °C.

SN54107, SN54LS107A . . . J PACKAGE SN74107 . . . N PACKAGE SN74LS107A . . . D OR N PACKAGE (TOP VIEW)



SN54LS107A . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

'107
FUNCTION TABLE

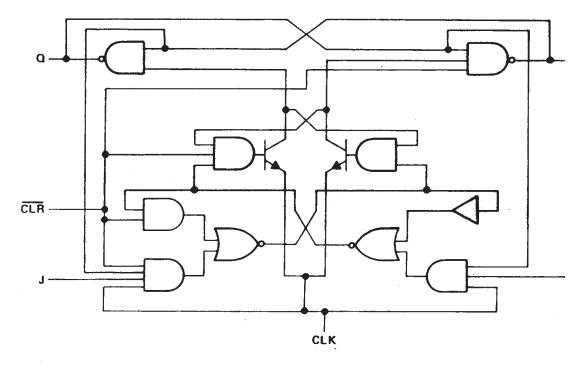
	INPU	OUTPUTS			
CLR	CLK	J	К	Q	ā
L	×	Х	Х	L	Н
Н	ır	L	L	α_0	\bar{a}_0
Н	T	Н	L	н	L
Н	. 1	L	н	L	Н
н	л	Н	н	TOG	GLE

'LS 107A FUNCTION TABLE

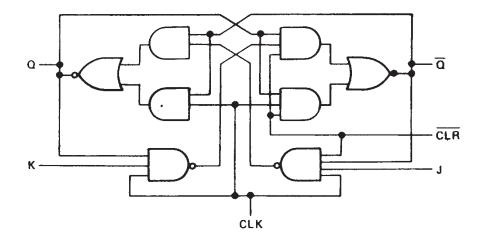
	INPU	OUTPUTS				
CLR	CLK	J	К	α	₫	
L	×	Х	Х	L	H	
н	1	L	L	σ_0	\bar{a}_0	
н	4	Н	L	н	L	
н	1	L	Н	L	н	
н⊦	4	H.	Н	TOGGLE		
н	н	X	×	△0	\overline{a}_0	



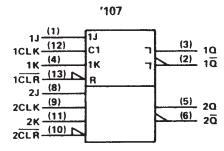
logic diagrams (positive logic)

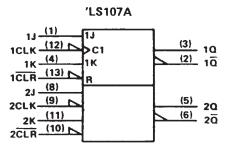


'LS107A



logic symbols†



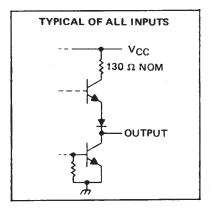


[†]These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for D, J, and N packages.

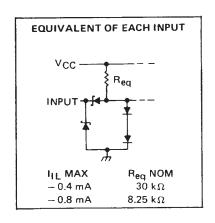
schematic of inputs and outputs

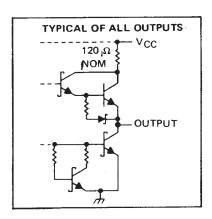
I₁L MAX R_{eq} NOM - 1.6 mA 4 kΩ - 3.2 mA 2 kΩ





'LS107A





absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)	7 V
Input voltage: '107	
1 \$107Δ	
Operating free-air temperature range: \$N54'	55°C to 125°C
\$N74'	U C to /U C
Storage temperature range	$\dots -65^{\circ}$ C to 150° C

NOTE 1: Voltage values are with respect to network ground terminal.



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recommended operating conditions

				SN54107			SN74107		
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		4.5	5	5.5	4.75	5	5.25	V
VIH	High-level input voltage		2			2			V
VIL	Low-level input voltage				0.8			8.0	V
ЮН	High-level output current				- 0.4			- 0.4	mA
IOL	Low-level output current				16			16	mA
		CLK high	20			20			
tw	Pulse duration	CLK low	47			47			ns
		CLR low	25			25			
t _{su}	Input setup time before CLK1		0			0			ns
t _h	Input hold time-data after CLK1		0			0			ns
TA	Operating free-air temperature		- 55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DA C	AMETER	TEST CONDITIONS†			SN5410	7		SN7410	7	UNIT	
PARAMETER		TEST CONDITIONS!		MIN	TYP‡	MAX	MIN	TYP‡	MAX	וואט	
v_{IK}		V _{CC} = MIN,	I ₁ = - 12 mA				- 1.5			– 1.5	V
Vон		V _{CC} = MIN,	V _{IH} = 2 V,	V _{IL} = 0.8 V,	2.4	3.4		2.4	3.4		V
VOL		V _{CC} = MIN, I _{OL} = 16 mA	V _{IH} = 2 V,	V _{1L} = 0.8 V,		0.2	0.4		0.2	0.4	٧
l _l		V _{CC} = MAX,	V ₁ = 5.5 V				1			1	mA
1	J or K	V _{CC} = MAX,	V ₁ = 2.4 V				40			40	
ΊΗ	All other	VCC - MAA,	V - 2.4 V				80			80	μΑ
1	J or K	V - MAY	V - 0.4 V				- 1.6			- 1.6	
ΙΙL	All other	V _{CC} = MAX,	V ₁ = 0.4 V			- 3.2				- 3.2	mA
los §		V _{CC} = MAX			- 20		- 57	- 18		- 57	mA
lcc1		V _{CC} = MAX,	See Note 2			10	20		10	20	mA

[†]For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

NOTE 2: With all outputs open, I_{CC} is measured with the Q and \overline{Q} outputs high in turn. At the time of measurement, the clock input is

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$ (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f _{max}				15	20		MHz
^t PLH	CLR	ā			16	25	ns
^t PHL	CLA	Q	$R_{\perp} = 400 \Omega$, $C_{\perp} = 15 pF$		25	40	ns
^t PLH	CLK	Q or $\overline{\Omega}$			16	25	ns
^t PHL	CLK	u or u			25	40	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



 $^{^{\}ddagger}$ All typical values are at V_{CC} = 5 V, T_A = 25 ° C.

[§]Not more than one output should be shorted at a time.

[¶]Average per flip-flop.

recommended operating conditions

			S	N54LS1	07A	S	UNIT		
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
Vcc	Supply voltage	_	4.5	5	5.5	4.75	5	5.25	V
ViH	High-level input voltage		2			2			V
VIL	Low-level input voltage				0.7			8.0	V
¹ ОН	High-level output current				- 0.4			- 0.4	mA
toL	Low-level output current				4			8	mA
f _{clock}	Clock frequency		0		30	0		30	MHz
	Dulan dunadan	CLK high	20			20			
t _w	Pulse duration	CLR low	25		;	25		,	ns
	0	data high or low	20	20		20			
t _{su}	Setup time before CLK #	CLR inactive	25			25			ns
th	Hold time-data after CLK↓		0			0			ns
TA	Operating free-air temperature		- 55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

			FOT COMPLETION	uct	SN	54LS10	7A	SN	UNIT			
PARAMETER		TEST CONDITIONS [†]		MIN	TYP‡	MAX	MIN	TYP‡	MAX	UNII		
VIK		V _{CC} = MIN,					- 1.5			– 1.5	· V	
Vон		V _{CC} = MIN, I _{OH} = 0.4 mA	V _{IH} = 2 V,	VIL = MAX,	2.5	3.4		2.7	3.4		٧	
.,		V _{CC} = MIN, I _{OL} = 4 mA	VIL = MAX,	V _{IH} = 2 V,		0.25	0.4		0.25	0.4	.4	
VOL		V _{CC} = MIN, I _{OL} = 8 mA	VIL = MAX,	V _{IH} = 2 V,					0.35	0.5		
	J or K						0.1			0.1		
1	CLR	V _{CC} = MAX,	V ₁ = 7 V	7 V		0.3	0.3		0.3		mA	
	CLK				0		0.4			0.4		
• • • •	J or K						20			20		
ЧН	CLR	V _{CC} = MAX,	V1 = 2.7 V				60			60	μΑ	
	CLK		•				80			80		
	JorK	V - MAY	V = 0.4.V				- 0.4	- 0.4		mA		
HL	CLR or CLK	V _{CC} = MAX,	V ₁ = 0.4 V				- 0.8			- 0.8		
los§		V _{CC} = MAX,	See Note 4		- 20		- 100	- 20		- 100	mA	
Icc (Total)	V _{CC} = MAX,	See Note 2			4	6		4	6	mA	

[†]For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

 \ddagger All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$ (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST COM	MIN	TYP	MAX	UNIT	
fmax					30	45		MHz
tPLH			$R_L = 2 k\Omega$,	C _L = 15 pF		15	20	ns
tPHL	CLR or CLK	Q or Q	The second			15	20	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



[§] Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

NOTE 2: With all outputs open, I_{CC} is measured with the Q and \overline{Q} , outputs high in turn. At the time of measurement, the clock input is grounded.

NOTE 4: For certain devices where state commutation can be caused by shorting an output to ground, an equivalent test may be performed with V_O = 2.25 V and 2.125 V for the 54 family and the 74 family, respectively, with the minimum and maximum limits reduced to one half of their stated values.

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